

**Search Notes**

Application/Control No.

10/517,026

Examiner

Jason M. Perilla

Applicant(s)/Patent under  
Reexamination

LECLAIR, PHILIPPE

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	316	9/24/2007	JP
	295	9/24/2007	JP
	340	9/24/2007	JP
	346	9/24/2007	JP

**INTERFERENCE SEARCHED**

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375	316	9/24/2007	JP
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB	9/24/2007	JP
Inventor Name Search	9/24/2007	JP
NPL Search IEEE Explore	9/24/2007	JP